

## Notice of References Cited

Application/Control No. 09/942,290	MAD ant(s)/Pater Reexamination LIN, CHARLES	1		
Examiner	Art Unit			
David L. Ometz	2653	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2001/0022712	09-2001	Funayama et al.	360/317
	В	US-2002/0034043	03-2002	Okada et al.	360/125
	'n,	US-2002/0036871	03-2002	Yano et al.	360/317
	Ď.	US-2002/0171975	11-2002	Plumer et al.	360/125
	Ę	US-2002/0176214	11-2002	Shukh et al.	360/317
	F	US-6,513,228	02-2003	Khizroev et al.	29/603.14
	G	US-2004/0061973	04-2004	Crue et al.	360/126
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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